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Scanning tunneling microscopy, high-resolution electron energy loss spectroscopy, and theoretical studies of trimethylphosphine (TMP) on a Si(111)- (7×7) surface

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Abstract

Adsorption of trimethylphosphine (TMP) on a Si(111)- (7×7) surface was studied using scanning tunneling microscopy (STM), high-resolution electron energy loss spectroscopy (HREELS), and theoretical calculations. It was found from STM and HREELS that most of the TMP molecules are adsorbed molecularly on center adatom sites at room temperature. A semi-empirical calculation (AM1 method) verified that this is energetically favorable. It is also found that one of the protrusions (unoccupied state images) on the center adatom site moves to the rest atom site and three protrusions (occupied state images) appear on the corner and center adatom sites in the second scan (interval of a few minutes). The results of a theoretical calculation indicate that adsorption of the three CH₃ groups and the P atom on the adatom and rest atom sites, respectively, is energetically favorable. This explains the STM mages well. The HREELS result suggests that the CH₃ group is split off and dissociated into CH₂ (or CH) and H upon heating the sample. The result of the theoretical calculation shows that the dissociation of CH₃ into CH₂ and H is energetically preferable when CH₂ is bridged between an Si adatom and an Si atom in the second layer and H s on the rest atom site. © 1999 Elsevier Science B.V. All rights reserved.

Keywords: Chemisorption; Electron energy loss spectroscopy; Low index single crystal surfaces; Scanning tunneling microscopy; Semiconducting surfaces; Semi-empirical models model calculations; Silicon; Trimethylphosphine

1. Introduction

Adsorption, decomposition, and surface reaction of gases have been widely studied on semiconductor surfaces because they are very important for not only basic science but also for device applications. Recently fabrications of nanometer

* Corresponding author. Fax: +81-53-4781651. E-mail address: royfuku@ipc.shizuoka.ac.jp (Y. Fukuda) scale structures and atomically controlled devices (such as quantum dots and wires, superlattices, etc.) have been developed using metalorganic chemical vapor deposition (MOCVD) and chemical beam epitaxy (CBE). The first step in the fabrication of the structures and devices is adsorption and decomposition of metalorganic compounds as precursors in MOCVD and CBE. From the above point of view, many studies of the adsorption and decomposition of the precursors

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on the semiconductor substrates have been reported [1].

Since scanning tunneling microscopy (STM) can image an individual atom on surfaces in certain electronic states, many studies have been reported on well-defined surfaces. In particular, an Si(111)- (7×7) surface is very interested because Si adatoms with several different electronic states coexist on the reconstructed surface. Therefore, it is expected that molecules adsorb and decompose on specific sites. For examples, it has been reported that C₂H₂ [2] and AlCl₃ [3] are adsorbed preferentially on the center adatom sites whereas PH3 and NH_3 are adsorbed on the rest atom sites [4-6]. It was found that trimethylphosphine (TMP) [(CH₃)₃P], which is one of the useful precursors for phosphorus in MOCVD, adsorbs preferentially on the center adatom sites and that most of the molecules adsorbed on the corner adatom sites migrate to the center adatom sites after a few minutes [7].

In this work three protrusions arranged in a triangular shape are found in STM images when the TMP molecule migrates from the center adatom site to the rest atom site. The STM image, however, cannot distinguish the atoms and molecules on the surfaces. Therefore, we studied the adsorption and decomposition of TMP on the Si(111)-(7 \times 7) surface in detail using high-resolution electron energy loss spectroscopy (HREELS). Theoretical calculations were also performed to clarify the experimental results.

2. Experimental

An n-type (phosphorus-doped) Si(111) sample (~2 Ω cm) was used for the experiments. It was resistively heated at 1523 K to remove surface oxides. The cleanness of the (7×7) surface was confirmed by Auger electron spectroscopy (AES), low-energy electron diffraction (LEED), and STM. After the clean sample had been exposed to 1 L (=10⁻⁶ Torr s) TMP gas in the preparation chamber, it was transferred to an analytical chamber. STM measurements were carried out at 1.5 and -1.5 V (sample bias) at constant currents.

The scanning tunneling microscope (JSTM-

4500XT, JEOL) is mounted in an ultrahigh vacuum chamber (base pressure, below 1×10^{-10} Torr) with a preparation chamber. LEED and AES facilities, an sputter ion gun, and a gas inlet line are installed in the preparation chamber.

An HREELS apparatus, which was built by ourselves, was used to examine chemical species on the surface exposed to TMP. A typical resolution was about 10 meV. The HREELS spectra were measured after the sample had been exposed to TMP at 110 and 300 K, and subsequently annealed at various temperatures.

3. Experimental results and discussion

Fig. 1 shows STM unoccupied (Fig. 1a,c) and occupied (Fig. 1b,d) state images for the Si(111)- (7×7) surface exposed to TMP at RT. The images were measured in the first (Fig. 1a,b) and second (Fig. 1c,d) scans (interval of about a few minutes) of the same area. Five bright protrusions are seen in the unoccupied state images (Fig. 1a), where the protrusions are on the center adatom sites. This is consistent with the previous result that most (about 88%) of the protrusions are on the center adatom site [7]. One (arrow) of them becomes less bright for the unoccupied state images (Fig. 1c) than that in Fig. 1a. A similar less bright protrusion is seen on the right-hand side in Fig. 1a. The less bright protrusions are found to be located on the rest atom site. In contrast, the protrusion (arrow in Fig. 1b) in the occupied state images changes into the three in Fig. 1d. Similar protrusions are also seen on the right-hand side ir Fig. 1b. The number of the groups of three protrusions arranged in a triangular shape is low a 300 K. Their number increased at elevated temperature. One (the corner adatom site) of the three is brighter than the others.

A cross-sectional plot along the line (between the corner holes) in Fig. 1a is shown in Fig. 2. Five peaks are found in the plot. D and E correspond to the center adatom sites (in the unfaulted half unit cell) without adsorption of TBP. A, C, and B correspond to the corner and center adatom and rest atom sites (in the faulted half unit cell)

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Fig. 1. STM unoccupied (a,c) and occupied (b,d) state images for the Si(111)- (7×7) surface exposed to TMP (1 L) at room temperature (RT) measured at bias voltages of 1.5 and -1.5 V, respectively. The images were measured in the first (a,b) and second interval of about a few minutes) (c,d) scan of the same area.

respectively. A, B, and C are higher than D and E. which is due to adsorption of CH_3 (A and C) and P (B). This will be discussed later.

Since the intensity of HREELS spectra for the Si(111)-(7 \times 7) surface exposed to the TBP gas (1 L) was weak, the HREELS measurements were carried out on the sample exposed to 30 L and 6 L of TBP. Comparison of the STM image for the surface exposed to 1 L with those for 30 L and 6 L indicated that all are essentially the same except for the number of the adsorbed TBP molecules. The HREELS spectra of the Si(111)-(7 \times 7) surface exposed to TMP (30 L) at 110 K (a) and

subsequently heated at 270 K (b) are displayed in Fig. 3. Sharp vibration peaks are found at 2930, 1410, and 938 cm⁻¹ and shoulders at about 1282 and 706 cm⁻¹. They can be ascribed to $v(CH_3)$, $\delta_a(CH_3)$, $\rho_r(CH_3)$, $\delta_s(CH_3)$, and $v_a(PC)$ [8–10], where v, δ_a , ρ_r , δ_s , and v_a correspond to stretching, asymmetric deformation, rocking, symmetric deformation, asymmetric stretching vibrations. Most of the peaks do not change in wavenumber except $v_a(PC)$ at 270 K where a weak peak appears at 683 cm⁻¹. Since a multilayer of TMP is formed at 110 K and the TMP would be chemisorbed with P at 270 K [11], the $v_a(PC)$ and



Fig. 2. Cross-sectional plot along the line (between the corner holes) in Fig. 1a.



Fig. 3. HREELS spectra of the Si(111)- (7×7) surface exposed to TMP (30 L) at 110 K (a) and subsequently heated at 270 K (b).

 $v_{s}(PC)$ peaks are observable at 110 and 270 K, respectively, as observed on a Pt(111) surface [11]. The broad peak at about 2219 cm⁻¹ and a shoulder at about 1640 cm⁻¹ would be combination bands of $\delta_{a}(CH_{3}) + \rho_{r}(CH_{3})$ and $v_{a}(PC) + \rho_{r}(CH_{3})$, respectively. The shoulder at about 3188 cm^{-1} would be due to the combination band of $v(CH_3)$ with a low wavenumber mode which is superimposed on an intense elastic peak.

HREELS spectra of TMP (6 L) on the Si(111)- (7×7) surface annealed at various temperatures are shown in Fig. 4. Clear vibration peaks at 2960, 1416. and 952 cm^{-1} are found in Fig. 4a. They correspond to $v(CH_3)$, $\delta_a(CH_3)$, and $\rho_r(CH_3)$, respectively, although the wavenumbers are higher than those in Fig. 3b. This would be due to the isolated TMP molecule chemisorbed on the surface. Shoulders at about 1280 and 700 cm^{-1} are also seen. The presence of the latter band indicates that most of the CH₃ group is bonded to the P atom at 300 K. Upon heating the sample at 400 K, a new peak appears at 2070 cm⁻¹. The 2960 and 952 cm^{-1} peaks are shifted to 2928 and 864 cm⁻¹, respectively, at 500 K and the 2070 cm⁻¹ peak increases in intensity. The 2070 cm⁻¹ peak can be ascribed to v(SiH)[12] which is due to dissociation



Energy Loss (cm⁻¹)

Fig. 4. HREELS spectra of the Si(111)- (7×7) surface exposed to TMP (6 L) at 300 K (a) and subsequently heated at 350 (b), 400 (c), 500 (d), 600 (e), 700 (f), 800 (g), 900 (h), 1000 (i), and 1200 K (j).

about 3188 cm^{-1} **n** band of $v(CH_3)$ which is superim-

L) on the Si(111)ious temperatures ion peaks at 2960, in Fig. 4a. They). and $\rho_r(CH_3)$, umbers are higher uld be due to the orbed on the surand 700 cm⁻¹ are tter band indicates bonded to the P e sample at 400 K, ⁻¹. The 2960 and 28 and 864 $\rm cm^{-1}$, $2070 \text{ cm}^{-1} \text{ peak}$ cm⁻¹ peak can be due to dissociation



500 3000 3500 4000 m⁻¹)

 (7×7) surface exposed mtly heated at 350 (b), (g). 900 (h), 1000 (i),

increases at 400 and 500 K. This implies that the **H**₃ group bonded to the phosphorus atom is hanged in the vibration mode. Two possible zes would occur: one is the splitting-off of the zetnvi group bonded to the P atom (electronega $rac{1}{2} = 2.1$) to Si (1.7) and the other is the formaof CH_x (x=1 and 2) on the surface. The mer and the latter lead to a decrease [13] and in increase [14] in the wavenumber of v(C-H), respectively, resulting in increase in the FWHM : the 2070 cm^{-1} peak. The splitting-off also jecreases the wavenumber of $\delta_a(CH_3)$ owing to the low electronegativity of the Si atom [14], which is in good agreement with the result that the 1416 cm^{-1} peak is shifted to 1392 cm^{-1} at 500 K. Since the 2070 cm^{-1} peak is observed between 400 and 900 K, both the splitting-off and the formation of CH_x would occur. The v(SiH) peak and 40 cm^{-1} band, which can be assigned to $\delta(\text{SiH})$ [2], increase to 900 K. The feature in the spectral change between 600 and 900 K is that the new rack appears at about 760 cm⁻¹ and that the 1410 and 2960 cm^{-1} peaks are shifted to 1390-1340 $2930-2890 \text{ cm}^{-1}$, respectively. Since .:nd (CH₂), δ (CH₂), and ρ (CH₂) modes were observed at about 2900, 1362–1382, and 776–745 cm⁻¹ for S₁H₃CH₂SiH₃ [15] and GeH₃CH₂SiH₃ [16], the above feature would be due to formation of CH₂ species on the surface. Similar peaks have been cound in the decomposition of trimethylgallium on GaAs(001) [17]. The v(CH), δ_{as} (CH), ρ_{as} (CH), and $\rho_s(CH)$ modes were found at 2890, 1315, 970, and 730 cm⁻¹, respectively on the Si(111)-(7 \times 7) surface exposed to acetylene [18]. Since they are superimposed on the bands between about 500 and 1350 cm⁻¹ in Fig. 4d–h, it is not clear that the CH species are formed on the surface. The v(SiC)reak [19] is observed at about 850 cm⁻¹ at 1200 K. The weak shoulder at about 500 cm^{-1} , which can be ascribed to v(SiP) [20], is seen between 600 and 1000 K although it is superimposed on a steep background. This is consistent with the result that P atoms are desorbed from the Si(111)-(7 \times 7) surface at about 1000 K [20]. The species

 $P(CH_3)_3$, $P(CH_3)_2$, and $P(CH_3)$ are not distin-

guished because of a limited resolution [8,9,21].

of the CH₃ group. The full width at half-maximum

(FWHM) of the peak at about 2928 cm^{-1}

The HREELS result showed that most of the CH₃ groups are bonded to the P atom at 300 K. However, taking account of the result that the splitting-off of the CH₃ group, the formation of CH_x, and the increase in the number of the three protrusions are found at elevated temperature (above 400 K), the three protrusions in Fig. 1d would be the decomposition products CH₃ (or CH_x) and P.

4. Method of calculation and its verification

To study the energetics and geometry of the TMP molecule on the Si(111)- (7×7) surface, we used the advanced semi-empirical quantum-chemical AM1 method (Austin Model 1) [22]. This is a version of the modified intermediate neglect of differential overlap (MINDO) [23-25] realized in the frame of the CLUSTER-Z1 package [26,27]. This package allows us to optimize atomic configurations by minimizing the total energy gradients over all atomic coordinates. The calculation speed with the semi-empirical method is significantly greater than that with the ab initio method, but its accuracy depends strongly upon choosing the correct set of parameters. In particular, the AM1 method is usually parameterized to reproduce heats of atomization and molecular geometry. Therefore, the ability of the semi-empirical method to describe an arbitrary configuration of atoms must be verified. The AM1 method was recently verified for a silicon-phosphorus system [28,29] where P-Si and P-P bonds on the Si(100) surface were studied. It was found that the P-Si bonds are energetically preferable, which is in accordance with the STM result [30,31] and ab initio molecular orbital calculations [30]. All quantitative values (energy differences, bond lengths and angles) close to the known data [30,31] have been obtained. Before studying the TMP molecule on the Si(111)- (7×7) surface, test calculations of the TMP molecular geometry were carried out. A schematic structure of the TMP molecule is shown in the upper part of Fig. 5 and the calculated parameters for TMP in this work are compared with the result obtained by an ab initio Hartree-Fock calculation [32] (Table 1). The AM1 method

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Fig. 5. Schematic illustrations of the TMP molecule and the $Si_{145}H_{75}$ cluster modeled for the Si(111)-(7 × 7) surface. The circles (arrow) correspond to atoms (the rest atom, center and corner adatom sites) used as adsorption sites in the calculations.

Geometry of the TMP molecule

	P-C bond distance (Å)	C-H bond distance (Å)	C-P-C angle (°)
Our result	1.76	1.11	100.90
Hartree–Fock calculations	1.845	1.096	98.95

gives us a good accuracy for the calculations of the TMP molecule.

5. Theoretical results and discussion

The STM experiment indicated that the behaviors in adsorption and migration of the TMP molecule on the unfaulted and faulted regions of the (7 × 7) surface are similar [7]. Therefore, only the TMP molecule on the unfaulted region is studied. The $Si_{145}H_{75}$ cluster shown in Fig. 5 is used as a model of the Si(111)-(7 × 7) surface (the

unfaulted region) for our calculation. This cluster consists of four atomic layers and eight adatoms. All broken Si bonds were terminated by H atoms with the equilibrium Si—H distance, 1.46 Å. The initial Si coordinates were taken from the reported data [33] and then the cluster geometry was optimized by the AM1-CLUSTER-Z1 procedure. No symmetric restrictions were adopted in our calculation. The final atomic positions are in agreement with the previous data [33] within ± 0.05 Å.

To study the energetics of the TMP adsorption on the Si(111)- (7×7) surface, the TMP molecule was placed on three different sites: on the rest atom, the center and the corner adatom sites. These sites are marked by arrows in Fig. 5. The binding energies (BE) together with the P-Si and P-C bond lengths for the three cases are listed in Table 2. It is clear that the center adatom is a more favored site for the adsorption than the rest atom, which is in accordance with the experiment [7]. The BE for TMP on the center adatom site is lower by 0.09 eV than that on the corner adatom. From the experimental diagram of the distribution of adsorption sites [7], one can obtain the energy difference of 0.06 eV, which is in good agreement with the calculated result.

The rest atom is surrounded by three neighboring adatoms with dangling bonds. Each center and corner adatom is located close to two and one neighboring rest atoms, respectively. For dissociation of the TMP molecule, assuming that the P atom and three CH₃ groups adsorb on the rest atom and the adatom sites, respectively, the **BE** is found to be -2.67 eV which is lower by about 1 eV than that in the molecular adsorption. In other words, the dissociation of the TMP molecule on the rest atom is energetically possible. This can explain the STM result that the three bright protru-

Table 2

Binding energy and geometry parameters of the TMP molecule placed on the various sites of the Si(111)-(7 \times 7) surface

Site	Binding	P-Si	P-C
	energy (eV)	distance (Å)	distance (Å)
Center adatom	-1.94	2.38	1.77
Corner adatom	-1.85	2.38	1.77
Rest atom	-1.68	2.42	1.78

on. This cluster eight adatoms. ted by H atoms ce. 1.46 Å. The om the reported metry was optiprocedure. No d in our calculare in agreement ± 0.05 Å.

MP adsorption TMP molecule es: on the rest r adatom sites. in Fig. 5. The h the P—Si and uses are listed in er adatom is a on than the rest the experiment r adatom site is corner adatom. the distribution brain the energy good agreement

three neighbor-Each center and b two and one by. For dissocining that the P orb on the rest ively, the BE is ower by about adsorption. In TMP molecule ssible. This can e bright protru-

the TMP molecule 7 × 7) surface P-C

.)	distance (Å)		
	1.77		
	1.77		
	1.78		

sions (occupied state image) appear on the adatom sites and new one (unoccupied state image) on the rest atom site after the second scan (Fig. 1c and d). In this case the P-Si distance is 2.42 Å and the C-Si distance is 1.85 and 2.08 Å for the center and corner adatom sites, respectively.

To make clear the changes in the STM images after the second scan, the calculation of the Si(111 μ 7×7) has been carried out assuming the same above configuration. Since the AM1 method does not correctly describe silicon electronic states it gives, for example, a forbidden gap of several eV), we used here the ab initio local density method (the so-called discrete variation cluster version) in a cluster approach [34]. The cluster size was 50: $Si_{18}H_{19} + PC_3H_9$. Calculated partial densities of states for P and CH₃ adsorbed on the various sites are plotted in Fig. 6. One can see that the CH₃ groups have peaks of occupied states between the Fermi level and -1.5 eV. The phosphorus atom also has some states near -1.5 eV.





However, the CH₃ is located higher above the silicon atom than the P atom: the CH₃ on the corner and center adatoms are higher by 0.91 and 0.72 Å, respectively, than the P atom on the rest atom. Thus, the CH3-tip distances are less than the P-tip, leading to the result that the P-tip tunnel currents at $V_s = -1.5 \text{ V}$ should be lower. Furthermore, the CH₃ image on the corner adatom site must be brighter than that on the center adatom, which is in good agreement with the STM images. However, the phosphorus atom has an intense peak at +0.2 eV but the CH₃ groups have a very low density of unoccupied states between the Fermi level and +1.5 eV. Thus, the P image at $V_s = +1.5$ V is brighter than that of CH₃. However, the P-tip distance is large, resulting in the low image intensity. All these calculation results are in excellent agreement with the experimental data in Fig. 1.

In order to understand why the TMP molecule is not dissociated on the adatoms, the calculation was performed in the case where the P atom is on the center adatom and one of the three CH_3 groups adsorbs on the rest atom. The binding energy is found to be positive (+5.46 eV). This suggests that dissociation of TMP on the adatom sites is not favorable.

Moving the CH₃ groups away from the P atom and optimizing all other coordinates, the energy difference was calculated to obtain the dissociation reaction barrier. The result of the calculation is plotted as a function of the P-C distance in Fig. 7. A sharp barrier with a 5.3 eV height is found at the P-C distance, 2.3 Å. Although the energy corresponds to about 6×10^4 K, it would be less than that, taking account of a transition state for the dissociation reaction. For comparison, the dissociation energy of the free TMP molecule [P(CH₃)₃ \rightarrow P+3CH₃] was calculated. It is found to be 10.4 eV which is twice as high as the dissociation energy of TMP on the Si(111)-(7×7) surface.

The BE of the P atom on the rest atom site was calculated for the surface without the CH₃ group. The energy is found to be -0.77 eV. On replacing the P atom with the Si rest atom, a BE of -6.08 eV is obtained. The BE of the CH₃ group on the Si adatom is also found to be -2.95 eV. This implies

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Fig. 7. The dissociation reaction barrier for the TMP molecule placed on the rest atom. The left minimum corresponds to the state in which the CH_3 group is bonded to the P atom. The right minimum corresponds to full dissociation (the CH_3 group is bonded to the Si adatom).

that the rest atom can be substituted by the phosphorus atom upon annealing, resulting in doping into the silicon substrate, while the CH_3 groups can be desorbed from the silicon surface when they are not dissociated. The latter is consistent with the experimental result (not shown here).

The BEs of CH₃, CH₂, and CH on the various sites were calculated to simulate the dissociation of the methyl group (Table 3). They are close, approximately from -2.4 to -2.9 eV. Thus, the $H_xC-Si(x=1-3)$ bond energy is higher than that (-2.3 eV) of the Si-Si bond. The H-C bond energy in the CH₃ group on the center and corner adatom sites is -3.2 eV, while that in the free





Fig. 8. Schematic view of the CH₃ (center) \rightarrow CH₂ (bridge)+ Π (rest) reaction on the Si(111)-(7 × 7) surface.

CH₃ group is -3.62 eV. The H-Si bond energin for the H atom on the center, corner, and re atom sites are approximately -2.7 eV. Therefore the dissociation, CH₃ \rightarrow CH₂+H, is not energed cally profitable. In fact, the total energy for (CH₂+H) is higher by 0.5-0.6 eV than that for CH₃. However, the dissociation reaction may be favorable if the H₂C-H bond breaking is accompanied by moving the CH₂ group to a bridge sibetween the Si adatom and one of the Si atoms the second layer (see Fig. 8 and Tables 4 and The result in Table 5 suggests that all configurtions for CH₂ (bridge)+H are energetical profitable. The most favorable configuration

Table 4 The total binding energy of $CH_2 + H$ on the various sites of $Si(111) \cdot (7 \times 7)$ surface		
Chemical species	Binding energy (
CH_{center} + H (center)	-2.00	
CH_2 (center) + H (corner)	-1.87	
CH_2 (center) + H (rest)	-1.98	
CH_2 (corner) + H (center)	-1.86	
CH_2 (corner) + H (rest)	-1.95	

Table 5

The total binding energy of CH_2 (bridge)+H on the varie sites of the Si(111)-(7 × 7) surface

Chemical species	Binding energy (e	
CH ₂ (corner, bridge) + H (center) CH ₂ (corner, bridge) + H (rest) CH ₂ (center, bridge) + H (center) CH ₂ (center, bridge) + H (rest)	$ \begin{array}{r} -2.61 \\ -2.87 \\ -2.93 \\ -3.24 \end{array} $	

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H₂ (bridged between the center adatom and Si **t** the second layer) + H (on the rest atom site). This is calculated in detail. The calculation was **erformed** in two parts. First, the H atom was noved away from the CH₃ in the rest atom irection. The energy is plotted in Fig. 9a as a **unction** of the C-H distance. Second, the CH₂ roup was moved to the bridge site in the following ray. The Si adatom-C bond was bent in the Si **i** com-C-Si atom (at the second layer) plane.

rest atom site

2.5

3

(center) \rightarrow CH₂ (bridge) + the result is shown in Fig. 9b. It is found that the \rightarrow surface.

H (rest)

 \mathbf{r}

the H-Si bond energinates y - 2.7 eV. Thereford z + H, is not energet the total energy for b - 0.6 eV than that for ation reaction may bond breaking is accongroup to a bridge sione of the Si atoms and Tables 4 and 5 ests that all configura t + H are energetical rable configuration

-3.24



-2

1

2

9. (a) Energy barrier for the H atom moving from CH_2 er) to the rest atom site. (b). Energy barrier for CH_2 = from the center adatom site to the bridge.

2

1.5

barrier height is rather high (approximately 3 eV) at about 2 Å for the CH_2-H distance. In contrast, the barrier is almost absent (only 0.08 eV) for the bond bending of Si-CH₂ and the whole binding energy of the (CH₂+H) complex reaches -1.26 eV at 78° where CH₂ is at the bridge site. The whole energy for the dissociation, CH₃ (center) \rightarrow CH₂ (bridge)+H (rest), is -0.72 eV. This is energetically favorable. This is also consistent with the HREELS result although the adsorption site for the CH₂ cannot be distinguished in the HREELS spectra.

Summarizing this work, adsorption of TMP on the Si(111)- (7×7) surface has been studied by STM, HREELS, and theoretical calculations. It was found by STM that most of the TMP molecules adsorb molecularly on the center adatom sites at RT. It was verified by the semi-empirical calculation (the AM1 method) that this is energetically favorable. After the second scan, one of the protrusions (unoccupied state images) on the center adatom site moved to the rest atom site and three protrusions (occupied state images) appeared on the corner and center adatom sites. The result of the theoretical calculation indicates that adsorption of the three CH₃ groups and the P atom on the adatom and rest atom sites, respectively, is energetically favorable. This explains the STM images well. The HREELS result suggests that the CH_3 group is split-off and dissociated into CH_2 (or CH) and H upon heating the sample. The energy for the dissociation reaction of CH₃ is calculated in detail as a function of the C-H bond length and of the Si-C angle. The result of the calculation shows that the dissociation of CH₃ into CH₂ and H is energetically preferable when CH₂ is bridged between the Si center adatom and the Si atom in the second layer and H is on the rest atom site.

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